

Application/Control	l No.
10/809,480	

Examiner
Andrew Hwa S. Lee

Applicant(s)/Patent under Reexamination
MIWA, YASUHIRO

Art Unit 2877

	o 01	RIGINAL	INTERNATIONAL CLASSIFICATION										
CLASS SUBCL			CLASS			CL	AIMED			NON-CLAIMED			
	06	G	01	С	3	/08			1				
	G	03	В	7	/099								
CLASS	SUBCLASS	ER BLOCK)	L	0.5			7099						
396	106			G	02	В	7	/28			1		
				G	03	В	13	/00			1		
				G	03	В	7	/097			1		
								1			1		
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(Assi	6/25/06				Total Claims Allowed: 6								
(Assistant Examiner) (Date)  (Legar Instruments Examiner) (Date)					NDR MB	EW) I (AMII	AEB) TEE	O.G. Print Claim(s)			O.G. Print Fig		

⊠ c	Claims renumbered in the same order as presented by applicant										☐ CPA			☐ T.D.		☐ R.1.47			
Final	Original		Final	Original		Final	Original	,	Final	Original		Final	Original		Final	Original		Final	Original
	1			31			61			91			121			151			181
	2			32			62			92			122			152			182
	3			33			63			93			123			153			183
	4	. 0		34			64			94			124			154			184
	5			35			65			95			125			155			185
	6			36			66			96			126			156			186
	7			37			67			97			127			157			187
	8			38			68			98			128			158			188
	9			39			69	]		99			129			159			189
	10			40			70			100			130			160			190
	11			41			71	]		101			131			161			191
	12			42			72			102			132			162			192
	13			43			73			103			133			163			193
	14	0		44			74			104			134			164			194
	15			45			75			105			135			165			195
	16			46			76	]		106			136			166			196
	17			47			77			107			137			167			197
	18		_	48			78	]		108			138			168			198
	19			49			79			109			139			169			199
	20			50			80			110			140			170			200
	21			51			81			111			141			171			201
	22			52			82			112			142			172			202
	23	ø		53			83			113			143			173			203
	24			54			84	]		114			144			174			204
	25			55			85			115			145			175			205
	26			56			86			116			146			176			206
	27			57			87			117			147			177			207
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	29			59			89			119			149			179			209
	30			60			90			120			150			180			210